



## IECQ Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.:	IECQ-L DEKRA 17.0004	Issue No.:	1	Status:	Current
Supersedes:		Issue Date:	2017/12/21	Org Issue:	2017/12/21
CB Reference No.:	DEKRA-C11A-001	Expiration:	2020/12/20		

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 China

The organization, facilities and procedures have been assessed and found to comply with the applicable requirements for Independent Testing Laboratory organization approval, in support of the IECQ system, which is in accordance with the Basic Rules IECQ 01 and Rules of Procedure IECQ 03-6 "Independent Testing Laboratory Assessment Program Requirements" of the IEC Quality Assessment System for Electronic Components (IECQ) and applicable requirements of ISO/IEC 17025: 2005 for the testing of electronic components under the IECQ.

**Scope:**

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**Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials**  
 -  
**See attached Schedule of Scope**  
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-- Attached Schedule: IECQ-L DEKRA 17.0004-S Rev1.pdf --

**Approved by Certification Body (CB): DEKRA Certification B.V.**

Meander 1051  
 Arnhem  
 Netherlands

Authorized person:  
**Ted Gaertner**



The validity of this certificate is maintained through on-going surveillance audits by the IECQ CB issuing this certificate.  
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## Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L DEKRA 17.0004

CB Certificate No.: DEKRA-C11A-001

Schedule Number: IECQ-L DEKRA 17.0004-S    Rev No.: 1    Rev. Date: 2017/12/21    Page 1 of 1

### 1. Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials

Description test	Standard	Remarks
Failure and material analysis of semiconductor IC, electronic components and PCB/PCBA, using FIB (Focused Ion Beam) and SEM ( Scanning electron microscope )	MIL-STD-883 Method 2018.4 JESD22A121 JESD201	Or customer specified test
Failure and material analysis of semiconductor IC, electronic components and PCB/PCBA, includes Electrical Analysis and Physical Analysis with Sample Preparation (Decap, X-section, etc)	MIL-STD-883 Method 2009.9 IPC-A-610; IPC-A-600 MIL-STD-883 Method 2008.4 JESD22A121; JESD201 IPC-TM-650 2.1.1; IPC-6012	Or customer specified test
Failure and material analysis of semiconductor IC, electronic components and PCB/PCBA, includes NDE (Non-destructive Testing)	MIL-STD-883 Method 2012.7 J-STD-035 J-STD-020	Or customer specified test
Accelerated lifetime simulation tests. (Includes Operating Life test / Early life failure rate test/ Endurance and Data retention test / Electro-Migration /Miscellaneous test )	JESD 47, JESD22-A108/A117, JESD61, MIL-STD-202/750/810/883, AEC-Q100; AEC-Q101, AEC-Q200,	Or customer specified test
Electromagnetic compatibility and electrostatic discharge test. (Includes HBM / MM / CDM / Latch Up )	JEDEC22-A114/A115/C101, EIA/JESD78, ANSI JEDEC ESDA JS001/JS002; AEC-Q100-002/003/004/011, AEC-Q101-001/002/005, JEITA ED4701; MIL-STD-883,	Or customer specified test

This schedule is only valid in conjunction with the referenced Certificate of Approval

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**DEKRA Certification B.V.** Meander 1051, Arnhem. Netherlands